

Application N	o. Ap	Applicant(s)			
10/669,534	СН	IEN, WEI-CHEN			
Examiner	Art	Unit			
Domoon E L	ovi 29.	44			

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENC	E(S)				
CLASS SUBCLASS	CLASS		SUBCLA	SS (ONE SUBCLASS	PER BLOCK)				
361 804	361	742	758 770	o C					
INTERNATIONAL CLASSIFICATION	439	65	66						
H 0 5 K 1/14									
H 0 1 R 13/24									
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Dameon E. Levi			KAMAND CUNI	:0	Total Claims Allo	owed: 11			
(Assistant Examiner) (Dat	۵)	CHIP	RVISØRY PATENT	EXAMINER					
7;	******************	TECHNOLOGY CENTER 2800			O.G.	O.G.			
	11/24	1111			Print Claim(s)	Print Fig.			
	Date)	(P)	imary Examinari	(Date) 0) 25 or \	7	3,4			
		- 		0/25/0/	•	V 1 7			
Claims renumbered in the	r as presei	nted by applicant	□СРА	☐ T.D.	☐ R.1.47				
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Final Original Original	Final	Original	Final	Final	Final	Final Original			
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1 1 31		61	91	121	151	181			
2 2 32		62	92	122	152	182			
3 3 3		63	93	123	153	183			
4 4 34		64	94	124	154	184			
5 5 35		65	95	125	155	185			
6 6 36 37		66 67	96	126	156	186			
8 8 38		68	98	128	158	188			
9 9 39		69	99	129	159	189			
10 10 40		70	100	130	160	190			
11 11 41		71	101	131	161	191			
12 42		72	102	132	162	192			
13 43 14 44		73	103	133	163	193			
14 44 15 45		74 75	104	134	164 165	194 195			
16 46		76	106	136	166	195			
17 47		77	107	137	167	197			
18 48		78	108	138	168	198			
19 49		79	109	139	169	199			
20 50		80	110	140	170	200			
21 51		81	111	141	171	201			
22 52		82	112	142	172	202			
23 53 24 54		83 84	113	143	173	203			
25 55		85	115	145	175	204			
26 56		86	116	146	176	206			
27 57		87	117	147	177	207			
28 58		88	118	148	178	208			
29 59		89	119	149	179	209			
30 60		90	120	150	180	210			